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INFORMATION DISCLOSURE CITATION

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Applicant

FINE, et al.

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Not yet assigned

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Issue Date	Name	Class	Sub-Class	Filing Date
<i>mk</i>	AA	5,348,002	Sep. 20, 1994	Caro			Apr. 23, 1992
<i>mk</i>	AB	5,792,668	Aug. 11, 1998	Fuller et al.			Apr. 15, 1996
<i>mk</i>	AC	5,941,821	Aug. 24, 1999	Chou			Nov. 25, 1997
<i>mk</i>	AD	6,049,728	Apr. 11, 2000	Chou			Nov. 12, 1998
<i>mk</i>	AE	6,400,972	June 4, 2002	Fine			Dec. 21, 1999
<i>mk</i>	AF	6,466,806	Oct. 15, 2002	Geva et al.			May 17, 2000
<i>mk</i>	AG	2002/0155615	Oct. 24, 2002	Novikov et al.			Feb. 5, 2002

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub-Class	Translation
<i>mk</i>	AH	WO 01/96872	Dec. 20, 2001	WIPO			N/A
<i>mk</i>	AI	WO 01/45553	June 28, 2001	WIPO			N/A
<i>mk</i>	AJ	WO 02/069791	Sep. 12, 2002	WIPO			N/A
<i>mk</i>	AK	0 282 234	Sep. 14, 1988	EP			N/A
<i>mk</i>	AL	WO 00/43759	July 27, 2000	WIPO			N/A

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

	AM	Feldman, Yuri, et al., "Time domain dielectric spectroscopy: An advanced measuring system". Rev. Sci. Instrum., vol. 67, no. 9, pp. 3208-3216, September 1996.
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Examiner

Matthew Kerner

Date Considered

4/13/2005

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609.
Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to Applicant.